

Notice of References Cited	Application/Control No. 10/596,381	Applicant(s)/Patent Under Reexamination DE VAAN, ADRIANUS JOHANN	
	Examiner JENNIFER ZUBAJLO	Art Unit 2629	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0063806	05-2002	Ouchi et al.	348/745
*	B	US-2001/0050661	12-2001	Noda et al.	345/32
	C	US-			
	D	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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